S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/811,316	PACK ET AL.	
Examiner	Art Unit	
SANG KINA	3654	

SEARCHED			
Class	Subclass	Date	Examiner
242	418	6/9/2006	SK
242	420	6/9/2006	SK
242	557	6/9/2006	SK
242	563	6/9/2006	SK
242	564	6/9/2006	SK
242	564,4	6/9/2006	SK
191	12.2A	6/9/2006	SK
191	12.2R	6/9/2006	SK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
of duted	A	9-11-07	511

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
John Nguyen: 242/418, 420, 557, 563, 584, 584.4	6/8/2006	SK
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